

Critical Die Quality Inspection

To help you maintain the stringent quality control standards required for your wire drawing equipment, Fort Wayne Wire Die offers a diverse line of wire die inspection microscopes. Specially designed to allow you to inspect the surface finish and wear patterns of your wire dies, your DM300 Series microscope will play a crucial role in your quality control system.

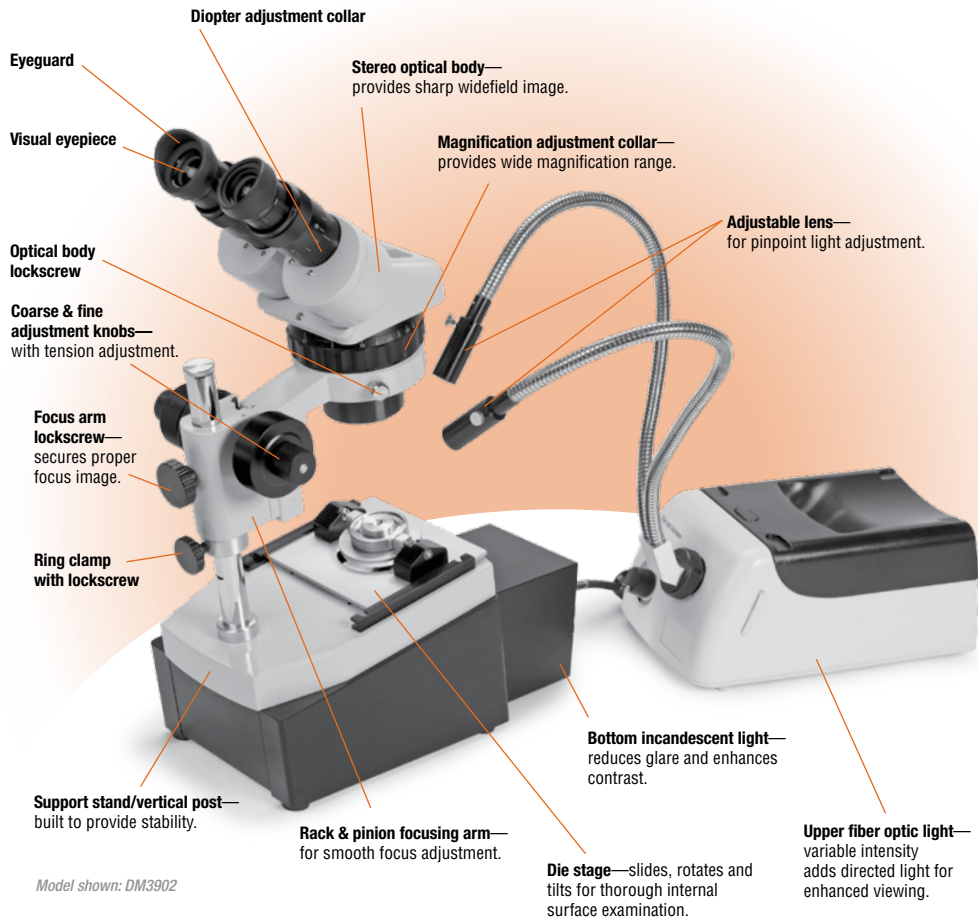


A Key to Maintaining Die Performance

Specifically designed for visual inspection of die geometry, Fort Wayne Wire Die's DM300 Series microscopes enable you to inspect the surface of your dies for better finished wire quality.

By combining a superior optical alignment with a specially adapted light source, the DM300 Series helps you locate surface flaws and wear patterns. Magnification capabilities allow you to evaluate proper die geometry and polish in dies as small as 0.050mm (.002"). In addition, the die stage slides, rotates and tilts providing a continuous rotational examination of the die's internal surface profile.

With a range of models, from the full-service DM390ZT to the economical DM340, there is a microscope perfect for your application. Setup and operation is easy. For more information, contact a Fort Wayne Wire Die representative.



DESCRIPTION	OBJECTIVE	TOTAL MAGNIFICATION	WORKING DISTANCE	FIELD DIAMETER
DM390ZT Full service model offers widest magnification range for basic carbide to fine precision diamond dies. <i>Trinocular</i> design features photographic capabilities (35mm, instant, or CCTV). For use with dies between 0.050mm–4mm (.002"–.150").	ZOOM 0.7–4.5x 6.5:1 Ratio	14x–90x *(21–135x)	86mm (3.4")	16.1mm–2.5mm (.64"–.1")
DM390Z Our most popular full service binocular model offers widest magnification range for basic carbide to fine precision diamond dies. For use with dies between 0.050mm–4mm (.002"–.150").	ZOOM 0.7–4.5x 6.5:1 Ratio	14x–90x *(21–135x)	86mm (3.4")	16.1mm–2.5mm (.64"–.1")
DM380 Dual objective special medium range binocular model for use with dies between 0.2mm–1mm (.008"–.040").	Dual 2x–4x	40x–80x *(60–120x)	64mm (2.5")	3.5mm–5.5mm (.14"–.21")
DM340 Dual objective binocular model designed for inspecting larger diameter dies above 1mm (.040")	Dual 1x–2x	20x–40x *(30–60x)	106mm (4.2")	5.5mm–11mm (.21"–.43")

*with optional 30x eyepiece.

Suggested Microscope Viewing Ranges	
Magnification	Hole Size (in)
120x–160x 0.05 and smaller	.002 and smaller
90x–120x 0.051–0.10	.00201–.004
60x–90x 0.101–0.25	.00401–.010
30x–45x 0.251–2.30	.0101–.090
10x–20x 2.301 and larger	.0901 and larger

Each microscope is available in 110V/60Hz or 230V/50Hz and features a die stage that accepts metric or inch size die casings. Please specify voltage and casing sizes when ordering. Standard eyepiece for each is 20x. Installation and operation manuals included. Optional accessories available.



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